



 <b>Form 1449 (Modified)</b>  <b>Information Disclosure Statement By Applicant</b>  <b>(Use Several Sheets if Necessary)</b>	<b>Atty Docket No.</b> <b>ALPSP149/AB US02044-</b> <b>Normal</b>  <b>Applicant:</b> <b>Kitagawa</b>  <b>Filing Date</b> <b>March 16, 2004</b>	<b>Application No.:</b> <b>10/802,649</b>  <b>Group</b> <b>2859</b>
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## **U.S. Patent Documents**

### **Foreign Patent or Published Foreign Patent Application**

## **Other Documents**

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	C1	Ulrich Grusemann, <i>et al.</i> "Integrated-Optical Wavelength Sensor With Self-Compensation Of Thermally Induced Phase Shifts By Use Of A LiNbO <sub>3</sub> Unbalanced Mach-Zehnder Interferometer" Applied Optics, Vol. 41, No. 29, October 10, 2002, Pages 6211-6219, XP 002290429, 2002

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<b>Form 1449 (Modified)</b>			<b>Atty Docket No.</b> ALPSP149	<b>Application No.:</b> Unassigned
<b>Information Disclosure Statement By Applicant</b>			<b>Applicant:</b> Hitoshi KITAGAWA	
(Use Several Sheets if Necessary)			<b>Filing Date</b> Herewith	<b>Group</b> Unassigned

#### U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
<i>JK</i>	A	6,643,431 B2	11/04/03	Hatayama et al.	—	—	
	B						
	C						
	D						
	E						
	F						
	G						
	H						
	I						

#### Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
<i>JK</i>	J	7-181087	07/18/95	Japan	—	—		
<i>JK</i>	K	2000-29079	01/28/00	Japan	—	—		
	L							
	M							
	N							

#### Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	O	
	P	
	Q	
Examiner <i>JK</i>		Date Considered <i>7/28/05</i>

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.